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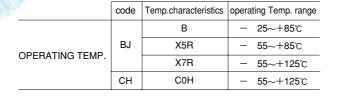




アレイ形積層セラミックコンデンサ ARRAY TYPE MULTILAYER CERAMIC **CAPACITOR**











特長 FEATURES

- ・2125形状で4回路構成であるため、より高密度、高効率な実装を実現
- ・1回路あたりの容量は1µFの大容量
- ・内部電極には、信頼性とコストパフォーマンスに優れたNiを使用していま
- · 4 circuits in 2125 package allows higher placement density and efficiency
- The capacitance in each circuit, F or B dielectric, is 1μ F
- · Internal electrode is nickel for increased cost performance and reliability

用途 APPLICATIONS

- ·一般電子機器用
- ・通信機器用 (携帯電話、PHS、コードレス電話etc)

- General electronic equipment
- · Communication equipment (mobile phone, PHS, cordless phone, etc.)

形名表記法 ORDERING CODE



定格電圧(VDC)	
J	6.3
L	10
E	16
Т	25
U	50



シリーズ名			
4	4連積層コンデンサ		
2	2連積層コンデンサ		

端子電	極
K	メッキ品

形状寸法 (EIA)L×W(m		IA)L×W(mm)
	110(0504)	1.4×1.0
	212(0805)	2.0×1.25
	316(1206)	3.2×1.6

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温度特	性
BJ	±10[%]
CH	0±60[ppm/°C]

公称前	電容量 (pF)
例	
104	100,000
105	1,000,000

容量許	容差	
М	±20	%
K	±10	%
F	±1pF	

製品厚	[み (mm)
В	0.6
Α	0.8
D	0.85
F	1.15

9

個別仕	·様
_	標準

10

包装	
Т	リールテーピング

A

当社管	理記号
	標准品
	标华 帕
	△= スペース



Rated voltage(VDC)		
J	6.3	
L	10	
E	16	
Т	25	
U	50	

Series name					
4	4 circuit multilayer				
4	capacitors				
2	2 circuit multilayer				
capacitors					

End termination Plated



Dimensions(case size)(mm)						
110(0504)	1.4×1.0					
212(0805)	2.0×1.25					
316(1206)	3.2×1.6					

Temperature characteristics code						
- п	X5R	-55~+85°C±15% -55~+125°C±15%				
ВЈ	X7R	-55~+125℃±15%				
СН	C0H	0±60[ppm/°C]				

Nominal capacitance(pF)						
example						
104	100,000					
105	1.000.000					

Capacitance tolerances(%)					
M	±20				
K	±10				
F	±1pF				

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Thickness(mm)					
В	0.6				
Α	0.8				
D	0.85				
F	1.15				

9

Specia	al code
_	Standard products

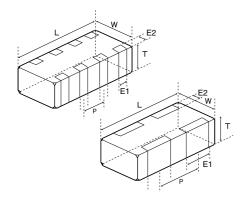


Packa	ging
Т	Tape & reel



Ų	ע	
1	nterna	al code
	Δ	Standard products
		A - Plank space

外形寸法 EXTERNAL DIMENSIONS



Type(EIA)	L	W	E1	E2	Р		Т
						В	0.60±0.06
□2K110	1.37±0.07	1.00±0.08	0.36±0.10	0.20±0.10	0.64±0.10	В	(0.024±0.003)
(0504)	(0.054±0.003)	(0.039±0.003)	(0.014 ± 0.004)	(0.008±0.004)	(0.025±0.004)	_	0.80±0.08
						Α	(0.031±0.003)
□4K212	2.00±0.10	1.25±0.10	0.25±0.10	0.25±0.15	0.50±0.10	D	0.85±0.10
(0805)	(0.079±0.004)	(0.049±0.004)	(0.010±0.004)	(0.010±0.006)	(0.020±0.004)	D	(0.033±0.004)
□2K212	2.00±0.10	1.25±0.10	0.50±0.20	0.25±0.15	1.00±0.10	D	0.85±0.10
(0805)	(0.079±0.004)	(0.049±0.004)	(0.020 ± 0.008)	(0.010±0.006)	(0.039 ± 0.004)	D	(0.033±0.004)
□4K316	3.20±0.15	1.60±0.15	0.40±0.20	0.30±0.20	0.80±0.10	F	1.15±0.15
(1206)	(0.126±0.006)	(0.063±0.006)	(0.016±0.008)	(0.012±0.008)	(0.031±0.004)	г	(0.045±0.006)

Unit: mm (inch)

概略バリエーション AVAILABLE CAPACITANCE RANGE

BJ/ X7R, BJ/ X5R														
	Туре	1410 2連			2125 2連 2125 4連					3216 4連				
			□2K ⁻	110		□2K	212	□4K212				□4K316		
	Temp.Char	BJ/	X7R	BJ/	X5R	BJ/	BJ/ X5R BJ/ X5R			BJ/ X5R				
Cap	VDC	25V	16V	10V	6.3V	10V	6.3V	25V	16V	10V	6.3V	16V	10V	6.3V
[μ F]	[pF:3digits]													
0.01	103	В												
0.022	223	В												
0.047	473		В											
0.1	104		В					D	D					
0.22	224			В						D				
0.47	474			Α						D				
1.0	105				Α	D					D	F	F	F
2.0	225						_ n							

※グラフ記号は製品厚みを表します。 Letters inside the shaded boxes indicate thickness.

CH/ C0H							
	Type 1410 2						
		□2K110					
	Temp.Char	CH / C0H					
Cap	VDC	50V					
[pF]	[pF:3digits]						
10	100	В					
12	120	В					
15	150	В					
18	180	В					
22	220	В					
27	270	В					
33	330	В					
39	390	В					
47	470	В					
56	560	В					
68	680	В					
82	820	В					
100	101	В					

※グラフ記号は製品厚みを表します。 Letters inside the shaded boxes indicate thickness.

			温度特性					
温度特性コード			Temperature chara	acteristics		静電容量許容差[%]	tans(%)	
Temp. char.Code	準拗	0.規格	温度範囲(℃)	基準温度(℃)	静電容量変化率	Capacitance tolerance	Dissipation factor	
	Applicab	le standard	Temperature range	Ref. Temp.	Capacitance change			
	JIS	В	−25~85	20	±10[%]	±20(M)		
BJ	EIA	X5R	−55~85	25	±15[%]	` ′	5.0%max.*	
	EIA	X7R	−55 ~125	25	±15[%]	±10(K)		
СН	JIS	СН	−55~125	20	±60[ppm/℃]	±10/K)	0.1%max.**	
OH	EIA	C0H	−55~125	25	±60[ppm/℃]	±10(K)	O. 1 /omax.	

* 10% : J2K110, J4K212 3.5%: 110type C<0.1μF 27pF以下 Q≥400+20 · C 30pF以上 Q≥1000

セレクションガイド Selection Guide













■1410TYPE (0504 case size)

2連タイプ (2 circuit type) _

定格電圧	形名	公 称 静電容量	温度特性	tan δ	実装条件 Soldering method	静電容量 許容差	厚み
<u> </u>		Capacitance	Temperature	Dissipation	R:リフロー Reflow soldering	Capacitance	Thickness
RatedVoltage Orde	Ordering code	[μ F]	characteristics	factor[%]Max.	W:フロー Wave soldering	tolerance	[mm](inch)
	T2K110 BJ103□B	0.01	B/X7R	3.5			
25V	T2K110 BJ223□B	0.022	D/X/11	3.3			
	T2K110 BJ104□B	0.1	B/X5R	5			0.6±0.06
16V	E2K110 BJ473□B	0.047	B/X7R	3.5			(0.024±0.002)
100	E2K110 BJ104□B	0.1	D/A/N		R	±20%[M] ±10%[K]	
	L2K110 BJ224□B	0.22	B/X5R	5		±10/0[K]	
100	L2K110 BJ474□A	0.47	D/ASH				0.040.00
6.3V	J2K110 BJ105□A*	1.0	BJ/X5R	10			0.8±0.08 (0.031±0.003)
0.37	J2K110 BJ225□A*	2.2	DJ/X5H	10			(0.031_0.003)

定格	形名	公	称	温度特性	Q	実装条件	静電容量	厚み
電圧	10 10	静電容	量			Soldering method	許容差	
_	0	Capacita	ance	Temperature	symbol	R:リフロー Reflow soldering	Capacitance	Thickness
RatedVoltage	Ordering code	[pF]		characteristics		W:フロー Wave soldering	tolerance	[mm](inch)
	U2K110 CH100FB	10						
	U2K110 CH120KB	12						
	U2K110 CH150KB	15			400+20 · C			
	U2K110 CH180KB	18						
	U2K110 CH220KB	22						
	U2K110 CH270KB	27		1				0.010.00
50V	U2K110 CH330KB	33		CH		R	±10%[K]	0.6±0.06
	U2K110 CH390KB	39						(0.024±0.002)
	U2K110 CH470KB	47						
	U2K110 CH560KB	56			1000 (0.1%)			
	U2K110 CH680KB	68						
	U2K110 CH820KB	82						
	U2K110 CH101KB	100						

■2125TYPE (0805 case size)

4連タイプ (4 circuit type) 🔔

定格	π/ 47	公 称	温度特性	$ an \delta$	実装条件	静電容量	厚み
電圧	形名	静電容量			Soldering method	許容差	
_		Capacitance	Temperature	Dissipation	R:リフロー Reflow soldering	Capacitance	Thickness
RatedVoltage	Ordering code	[μ F]	characteristics	factor[%]Max.	W:フロー Wave soldering	tolerance	[mm](inch)
25V	T4K212 BJ104□D	0.1					
16V	E4K212 BJ104□D	0.1	DVED	5		±20%[M]	0.85±0.1
10V	L4K212 BJ224□D	0.22 B/X5R 5		5	R	±10%[K]	(0.033±0.004)
100	L4K212 BJ474□D	0.47				±10%[K]	(0.033±0.004)
6.3V	J4K212 BJ105□D*	1.0	X5R	10			

■2125TYPE (0805 case size)

2連タイプ (2 circuit type) 🔔

定格	形名	公 称	温度特性	$tan \delta$	実装条件	静電容量	厚み
電圧	/// 10	静電容量			Soldering method	許容差	
电 庄 RatedVoltage	0.4	Capacitance	Temperature	Dissipation	R:リフロー Reflow soldering	Capacitance	Thickness
nated voltage	Ordering code	[μF]	characteristics	factor[%]Max.	W:フロー Wave soldering	tolerance	[mm](inch)
25V	T2K212 BJ105□D	1.0				±20%[M]	
16V	E2K212 BJ105□D	1.0	B/X5R	5		±10%[K]	0.85 ± 0.1
10V	L2K212 BJ105MD	1.0			R	±20%[M]	(0.033 ± 0.004)
6.3V	J2K212 BJ225MD*	2.2	X5R	10		±20/0[W]	

■3216TYPF (1206 case size) 4連タイプ (4 circuit type)

32101176	(1200 Case Size)	4注メーノ	(4 Circuit t	type) -						
	•		·							
定格	形名			公	称	温度特性	$tan \delta$	実装条件	静電容量	厚み
電圧	形 名 			静電	容量			Soldering method	許容差	
RatedVoltage	Ordering and			Capac	itance	Temperature	Dissipation	R:リフロー Reflow soldering	Capacitance	Thickness
nateu voitage	Ordering code			[μ	F]	characteristics	factor[%]Max.	W:フロー Wave soldering	tolerance	[mm](inch)
16V	E4K316 BJ105□F*								±20%[M]	1.15±0.15
10V	L4K316 BJ105□F			1.	0	B/X5R	5	R	±10%[K]	(0.045±0.006)
6.3V	J4K 316 BJ105□F								±10%[K]	(0.045±0.006)

形名の□には静電容量許容差記号が入ります。

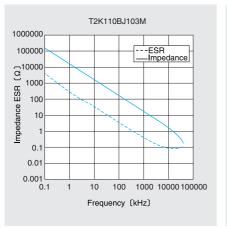
 $[\]hfill \square$ Please specify the capacitance tolerance code.

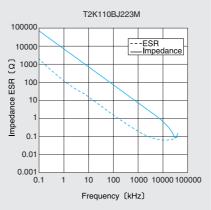
^{*}高温負荷試験の試験電圧は定格電圧の1.5倍

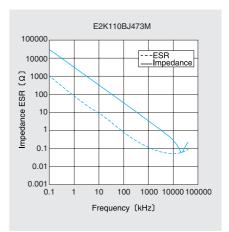
^{*}Test voltage of Loading at high temperature test is 1.5 time of the rated voltage.

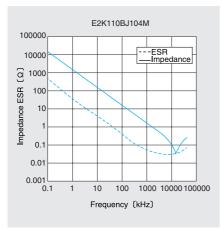
インピーダンス・ESR-周波数特性例 Example of Impedance ESR vs. Frequency characteristics

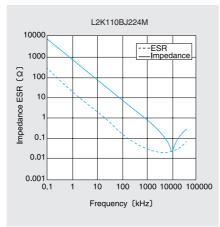
・当社積層セラミックコンデンサ例(Taiyo Yuden multilayer ceramic capacitor)

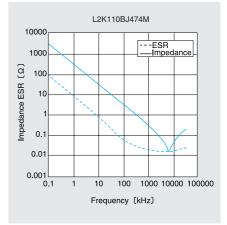


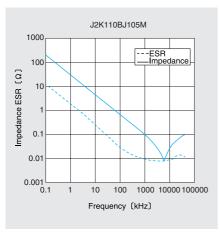


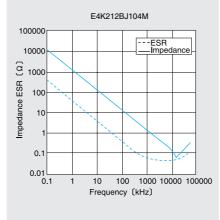


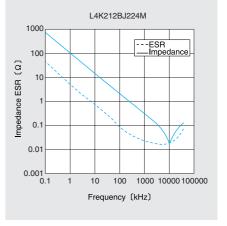


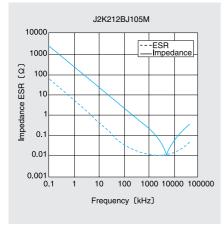


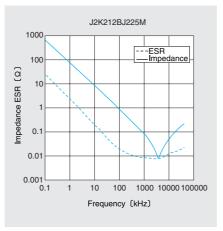












梱包 PACKAGING

①最小受注単位数 Minimum Quantity

■袋づめ梱包 Bulk packaging

形式(EIA) Type	製品厚み Thickness		標準数量 Standard quantity
туре	mm(inch)	code	[pcs]
☐MK105(0402)	0.5	V, W	
□VK105(0402)	(0.020)	W	
□MK107(0603)	0.8 (0.031)	Z	
□0K140(0504)	0.8 (0.031)	А	
□2K110(0504)	0.6 (0.024)	В	
	0.85 (0.033)	D	
□MK212(0805)	1.25 (0.049)	G	
□4K212(0805)	0.85 (0.033)	D	
□2K212(0805)	0.85 (0.033)	D	
	0.85 (0.033)	D	1000
□MK316(1206)	1.15 (0.045)	F	
□IVIK316(1206)	1.25 (0.049)	G	
	1.6 (0.063)	L	
	0.85 (0.033)	D	
	1.15 (0.045)	F	
□MK325(1210)	1.5 (0.059)	Н	
□IVIN325(1210)	1.9 (0.075)	N	
	2.0max (0.079)	Υ	
	2.5 (0.098)	М	

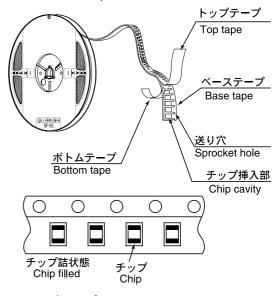
■テーピング梱包 Taped packaging

形式(EIA) Type	製品厚み Thickness			数量 I quantity cs]
	mm(inch)	code	紙テープ paper	エンボステープ Embossed tape
☐MK063(0201)	0.3 (0.012)	Р	15000	_
□MK105(0402)	0.5	V, W	10000	
□VK105(0402)	(0.020)	W	10000	
	0.5 (0.020)	V	4000	
□MK107(0603)	0.45 (0.018)	K	4000	_
	0.8 (0.031)	A Z	4000	
□2K110(0504)	0.8 (0.031)	Α	4000	
□2K110(0304)	0.6 (0.024)	В	4000	_
	0.45 (0.018)	К	4000	_
□MK212(0805)	0.85 (0.033)	D	4000	_
	1.25 (0.049)	G	_	3000
□4K212(0805)	0.85 (0.033)	D	4000	_
□2K212(0805)	0.85 (0.033)	D	4000	_
	0.85 (0.033)	D	4000	_
□MK316(1206)	1.15 (0.045)	F		
□4K316(1206)	1.25 (0.049)	G	_	3000
	1.6 (0.063)	L	_	2000
	0.85 (0.033)	D		
	1.15 (0.045)	F		
	1.5 (0.059)	Н	_	2000
□MK325(1210)	1.9 (0.075)	N	N	
	2.0max (0.079)	Υ	_	2000
	2.5 (0.098)	М	_	500
	1.9 (0.075)	Y	_	1000
□MK432(1812)	2.5 (0.098)	М		500
	3.2 (0.125)	U		300

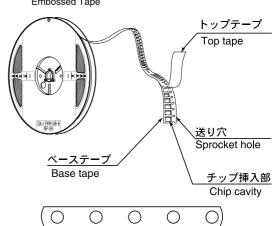
②テーピング材質 Taping material

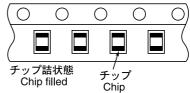
紙テープ

Card board carrier tape

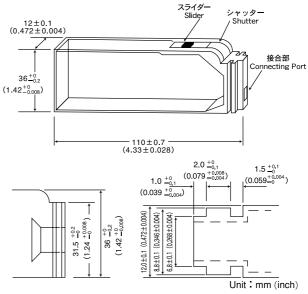


エンボステープ Embossed Tape



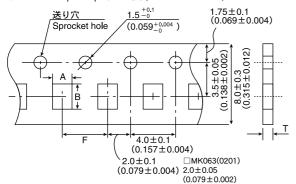


③バルクカセット Bulk Cassette



105, 107, 212形状で個別対応致しますのでお問い合せ下さい。 Please contact any of our offices for accepting your requirement according to dimensions 0402, 0603, 0805.(inch)

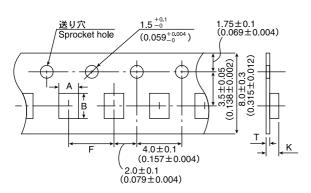
③テーピング寸法 Taping dimensions 紙テープ Paper Tape (8mm幅) (0.315inches wide)



Type	チッフ	プ挿入部	挿入ピッチ	テープ厚み
(EIA)	Chip	Cavity	Insertion Pitch	Tape Thickness
	Α	В	F	Т
□MK063(0201)	0.37±0.06	0.67±0.06	2.0±0.05	0.45max.
□IVIN003(0201)	(0.06±0.002)	(0.027±0.002)	(0.079±0.002)	(0.018max.)
□MK105(0402)	0.65±0.1	1.15±0.1	2.0±0.05	0.8max.
$\square VK105 (0402)$	(0.026±0.004)	(0.045±0.004)	(0.079±0.002)	(0.031max.)
	1.0±0.2	1.8±0.2	4.0±0.1	1.1max.
□MK107(0603)	(0.039±0.008)	(0.071±0.008)	(0.157±0.004)	(0.043max.)
□2K110(0504)	1.15±0.2	1.55±0.2	4.0±0.1	1.0max.
	(0.045±0.008)	(0.061±0.008)	(0.157±0.004)	(0.039max.)
□MK212(0805)	1.65±0.2	2.4±0.2		
□4K212(0805)	(0.065±0.008)	(0.094±0.008)	4.0±0.1	1.1max.
□2K212(0805)			(0.157±0.004)	(0.043max.)
	2.0±0.2	3.6±0.2		
□MK316(1206)	(0.079±0.008)	(0.142±0.008)		

Unit: mm(inch)

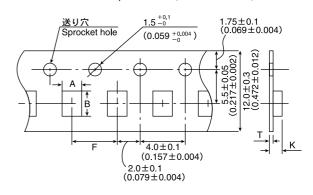
エンボステープ Embossed tape (8mm幅)(0.315 inches wide)



Туре	チッフ	[°] 挿入部	挿入ピッチ	テーフ	プ厚み
(EIA)	Chip	cavity	Insertion Pitch	Tape Th	ickness
	A B		F	K	Т
	1.65±0.2	2.4±0.2			
□MK212(0805)	(0.065±0.008)	(0.094±0.008)			
□MK316(1206)	2.0±0.2	3.6±0.2	4.0±0.1	2.5max.	0.6max
□4K316(1206)	(0.079 ± 0.008)	(0.142±0.008)	(0.157±0.004)	(0.098max.)	(0.024max.)
	2.8±0.2	3.6±0.2		3.4max.	
□MK325(1210)	(0.110±0.008)	(0.142±0.008)		(0.134max.)	

Unit: mm(inch)

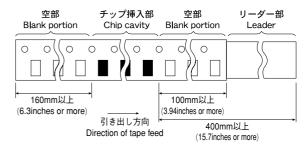
エンボステープ Embossed tape (12mm幅) (0.472inches wide)



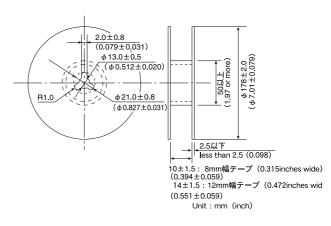
Туре	チッフ	[°] 挿入部	挿入ピッチ テーフ		プ厚み	
(EIA)	Chip	cavity	Insertion Pitch	Tape Th	Tape Thickness	
	A B		F	K	Т	
□MK432(1812)	3.7±0.2 (0.146±0.008)	4.9±0.2 (0.193±0.008)	8.0±0.1 (0.315±0.004)	4.0max. (0.157max.)	0.6max. (0.024max.)	

Unit: mm(inch)

④リーダー部/空部 Leader and Blank portion

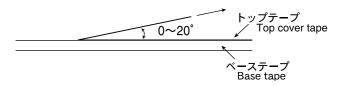


⑤リール寸法 Reel size



⑥トップテープ強度 Top Tape Strength

トップテープのはがし力は下図矢印方向にて0.1~0.7Nとなります。 The top tape requires a peel-off force of 0.1~0.7N in the direction of the arrow as illustrated below.



Multilayer Ceramic Capacitor Chips

			Specifi	ed Value		
It	tem	Temperature Com	pensating (Class 1)	High Permiti	vity (Class 2)	Test Methods and Remarks
		Standard	High Frequency Type	Standard Note1	High Value	
	Temperature	-55 to +125℃		B: −55 to +125°C	-25 to +85℃	High Capacitance Type BJ(X7R): −55~+125°C, BJ(X5R): −55~+88°C, C(X6S): −55~+10!
Range	Temperature	-55 to +125℃		F: -25 to +85°C B: -55 to +125°C	-25 to +85℃	E(Y5U): -30~+85°C, F(Y5V): -30~+85° High Capacitance Type BJ(X7R): -55~+125°C, BJ(X5R): -55~+8
Range	Temperature	-55 to +125 C		F: -25 to +85°C	-25 to +65C	C(X5S): -55~+85°C, C(X6S): -55~+810 E(Y5U): -30~+85°C, F(Y5V): -30~+88
3.Rated Volta	ge	50VDC,25VDC, 16VDC	16VDC 50VDC	50VDC,25VDC	50VDC,35VDC,25VDC 16VDC,10VDC,6.3VDC 4DVC	
4.Withstandin	g Voltage	No breakdown or dam-	No abnormality	No breakdown or dama		Applied voltage: Rated voltage×3 (Class 1)
Between ter	rminals	age				Rated voltage×2.5 (Class 2) Duration: 1 to 5 sec. Charge/discharge current: 50mA max. (Class 1,2)
5.Insulation F	lesistance	10000 MΩ min.		smaller.	$M\Omega .,$ whichever is the	Applied voltage: Rated voltage Duration: 60±5 sec.
6.Capacitanc	a (Tolorance)	0.5 to 5 pF: ±0.25 pF	0.5 to 2 pF : ±0.1 pF	Note 5 B: ±10%, ±20%	B: ±10%、±20%	Charge/discharge current: 50mA max. Measuring frequency:
о одражана	(roscance)	1 to 10pF: ±0.5 pF 5 to 10 pF: ±1 pF 11 pF or over: ±5% ±10% 105TYPERA, SA, TA, UA only 0.5~2pF: ±0.1pF 2.2~20pF: ±5%	2.2 to 5.1 pF : ±5%	F: +80 %	C:±10% ±20% E:-20%/+80% F:-20%/+80%	Class1: $1MHz\pm10\%(C\le1000pF)$ $1 k Hz\pm10\%(C>1000pF)$ $1 k Hz\pm10\%(C>1000pF)$ Class2: $1 k Hz\pm10\%(C\le22\mu F)$ $120Hz\pm10Hz(C>22\mu F)$ Measuring voltage: $Class1: 0.5\sim5Vrms(C\le1000pF)$ $1\pm0.2Vrms(C>1000pF)$ $Class2: 1\pm0.2Vrms(C\le22\mu F)$ $0.5\pm0.1Vrms(C>22\mu F)$ Bias application: None
7.Q or Tangen (tan &)	t of Loss Angle	Under 30 pF : Q≧400 + 20C 30 pF or over : Q≧1000 C= Nominal capacitance	Refer to detailed specification	B: 2.5% max.(50V, 25V) F: 5.0% max. (50V, 25V)	B:2.5% max. C、E、F:7% max. Note 4	Multilayer: Measuring frequency: Class1: $1MHz\pm10\%(C\le1000pF)$ 1 k $Hz\pm10\%(C\le1000pF)$ Class2: 1 k $Hz\pm10\%(C\le22_{\mu}F)$ 120 $Hz\pm10Hz(C>22_{\mu}F)$ Measuring voltage: Class1: $0.5\sim5Vrms(C\le1000pF)$ 1±0.2 $Vrms(C>1000pF)$ Class2: $1\pm0.2Vrms(C>1000pF)$ Class2: $1\pm0.2Vrms(C\le22_{\mu}F)$ Bias application: None High-Frequency-Multilayer: Measuring frequency: $1GHz$ Measuring gequipment: $1GHz$ Measuring gig: $1GHz$ Measuring jig:
8.Temperature Characteristic of Capacitance	(Without voltage application)	CK: 0±250 CJ: 0±120 CH: 0±60 CG: 0±30 PK: -150±250 PJ: -150±120 PH: -150±60 RK: -220±250 RJ: -220±120 RH: -220±60 SK: -330±250 SJ: -330±120 SH: -330±60 TK: -470±250 TJ: -470±120 TH: -470±60 UK: -750±250 UJ: -750±120	CH:0±60 RH:-220±60 (ppm/C)	B:±10%(-25~85°) F: +30 %(-25~85°) B(X7R):±15% F(Y5V): -82%	B:±10% (-25~+85°C) C:±20% (-25~+85°C) E:+20%/-55% (-25~+85°C) F:+30%/-80% (-25~+85°C) B(X7R, X5R): ±15% C(X5S, X6S): ±22% E(Y5U): +22%/-56% F(Y5V): +22%/-82%	According to JIS C 5102 clause 7.12. Temperature compensating: Measurement of capacitance at 20°C and 85°C shall be mad to calculate temperature characteristic by the following equation. (Ces - C20) C20 × ΔT × 10 6 (ppm/C) High permittivity: Change of maximum capacitance deviation in step 1 to Temperature at step 1: +20°C Temperature at step 2: minimum operating temperature Temperature at step 3: +20°C (Reference temperature) Temperature at step 4: maximum operating temperature Temperature at step 5: +20°C Reference temperature for X7R, X5R, X5S, X6S, Y5U and Y8 shall be +25°C
9.Resistance Substrate	to Flexure of	SL: +350 to -1000 (ppm/°C) Appearance: No abnormality Capacitance change: Within ±5% or ±0.5 pF, whichever is larger.	Appearance: No abnormality Capacitance change: Within±0.5 pF	Appearance: No abnormality Capacitance change: B, BJ, C: Within ±12.5% E, F: Within ±30%	6	Warp: 1mm Testing board: glass epoxy-resin substrate Thickness: 1.6mm (063 TYPE: 0.8mm) The measurement shall be made with board in the bent positi

Multilayer Ceramic Capacitor Chips

	Specified Value				
Item	Temperature Compensating (Class 1) High Permittivity (Class 2)			Test Methods and Remarks	
	Standard	High Frequency Type	Standard Note1	High Value	
10.Body Strength	_	No mechanical damage.	_	_	High Frequency Multilayer: Applied force: 5N Duration: 10 sec. Press Chip Chip L L W
1.Adhesion of Electrode	No separation or indicat	ion of separation of electr	ode.		Applied force: 5N Duration: 30±5 sec. (0201 TYPE 2N) Hooked jig Chip Cross-section
2.Solderability	At least 95% of terminal	electrode is covered by n	new solder.		Solder temperature: 230±5°C Duration: 4±1 sec.
13.Resistance to soldering	Appearance: No abnormality Capacitance change: Within ± 2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±2.5% Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±7.5% (B, BJ) Within ±15% (C) Within ±20% (E, F) tan \$\mathcal{s}\$: Initial value Note 4 Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality		Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Solder temperature: 270±5°C Duration: 3±0.5 sec. Preheating conditions: 80 to 100°C, 2 to 5 min. or 5 to 10 m 150 to 200°C, 2 to 5 min. or 5 to 10 m Recovery: Recovery for the following period under the stadard condition after the test. 24±2 hrs (Class 1) 48±4 hrs (Class 2)
14.Thermal shock	Appearance: No abnormality Capacitance change: Within ± 2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±0.25pF Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Capacitance change: Within $\pm 7.5\%$ (B, BJ) Within $\pm 15\%$ (C) Within $\pm 20\%$ (E , F) tan ε : Initial value Note 4 Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality		Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Conditions for 1 cycle: Step 1: Minimum operating temperature $^{+0}_{-3}$ °C 30 ± 3 m Step 2: Room temperature 2 to 3 m Step 3: Maximum operating temperature $^{-0}_{+3}$ °C 30 ± 3 m Step 4: Room temperature 2 to 3 m Number of cycles: 5 times Recovery after the test: 24±2 hrs (Class 1) 48±4 hrs (Class 2)
15.Damp Heat (steady state)	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5pF, whichever is larger. Q: C≧30 pF : Q≧350 10≦C<30 pF: Q≧275 +2.5C C<10 pF : Q≧200 + 10C C: Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within ±0.5pF, Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: B: Within $\pm 12.5\%$ F: Within $\pm 30\%$ tan δ : B: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: 50 M Ω μ F or 1000 M Ω whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ:Within $\pm 12.5\%$ C(X6S) Within $\pm 25\%$ C(X5S),E,F Within $\pm 30\%$ Note 4 $\tan \delta$: BJ: 5.0% max. C, E, F: 11.0% max. Insulation resistance: $50 \ M\Omega \ \mu F$ or $1000 \ M\Omega$ whichever is smaller. Note 5	Multilayer: Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Temperature: 40±2°C Humidity: 90 to 95% RH Duration: 500 +20 hrs Recovery: Recovery for the following period under the stadard condition after the removal from test chamber. 24±2 hrs (Class 1) 48±4 hrs (Class 2) High-Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 +20 hrs Recovery: Recovery for the following period under the stadard condition after the removal from test chamber. 24±2 hrs (Class 1)

Multilayer Ceramic Capacitor Chips

	Specified Value				
Item	Temperature Compensating (Class 1)		High Permittivity (Class 2)		Test Methods and Remarks
	Standard	High Frequency Type	Standard Note1	High Value	
16.Loading under Damp Heat	Appearance: No abnormality Capacitance change: Within \pm 7.5% or \pm 0.75pF, whichever is larger. Q: C \ge 30 pF: Q \ge 200 C $<$ 30 pF: Q \ge 100 + 10C/3 C: Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: C \leq 2 pF: Within \pm 0.4 pF C>2 pF: Within \pm 0.75 pF C: Nominal capacitance Insulation resistance: 500 M Ω min.	Appearance: No abnormality Capacitance change: B: Within $\pm 12.5\%$ F: Within $\pm 30\%$ tan δ : B: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: 25 M Ω μ F or 500 M Ω , whichever is the smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ C.E.F: Within $\pm 30\%$ Note 4 tans: BJ: 5.0%max. C.E.F: 11%max. Insulation resistance: 25 M Ω μ F or 500 M Ω , whichever is the smaller. Note 5	According to JIS C 5102 Clause 9. 9. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature: 40±2°C Humidity: 90 to 95% RH Duration: 500 + 24 hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. (Class 1,2) Recovery: Recovery for the following period under the stand condition after the removal from test chamber. 24±2 hrs (Class 1) 48±4 hrs (Class 2) High-Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 + 24 hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. Recovery: 24±2 hrs of recovery under the standard continuation after the removal from test chamber.
17.Loading at High Tempera- ture	Appearance: No abnormality Capacitance change: Within ±3% or ±0.3pF, whichever is larger. Q: C≥30 pF: Q≥350 10≤C<30 pF: Q≥275 +2.5C C<10 pF: Q≥200 + 10C C: Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within ±3% or ±0.3pF, whichever is larger. Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: B: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : B: 4.0% max. F: 7.5% max. Insulation resistance: $50~M\Omega~\mu F$ or $1000~M\Omega$, whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within±12.5% Within±20%; C: Within±25%(X6S) Within±30%(X5S) E, F: Within±30% Note 4 tan δ: BJ: 5.0%max. C, F, F: 11%max. Insulation resistance: 50 MΩ μF or 1000 MΩ, whichever is smaller. Note 5	According to JIS C 5102 clause 9.10. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature:125±3°C(Class 1, Class 2: B, BJ(X7R)) 85±2°C (Class 2: BJ,F) Duration: 1000 + 8 hrs Applied voltage: Rated voltage×2 Note 6 Recovery: Recovery for the following period under the st dard condition after the removal from test chamber. As for Ni product, thermal treatment shall be perforn prior to the recovery. 24±2 hrs (Class 1) 48±4 hrs (Class 2) High-Frequency Multilayer: Temperature: 125±3°C (Class 1) Duration: 1000 + 8 hrs Applied voltage: Rated voltage×2 Recovery: 24±2 hrs of recovery under the standard contion after the removal from test chamber.

Note 1 For 105 type, specified in "High value".

Note 2 Thermal treatment (Multilayer): 1 hr of thermal treatment at 150 +0 /-10 °C followed by 48±4 hrs of recovery under the standard condition shall be performed before the measurement.

Note 3 Voltage treatment (Multilayer): 1 hr of voltage treatment under the specified temperature and voltage for testing followed by 48±4 hrs of recovery under the standard condition shall be performed before the measurement.

Note 4, 5 The figure indicates typical inspection. Please refer to individual specifications.

Note 6 Some of the parts are applicable in rated voltage×1.5. Please refer to individual specifications.

Note on standard condition: "standard condition" referred to herein is defined as follows: 5 to 35°C of temperature, 45 to 85% relative humidity, and 86 to 106kPa of air pressure.

When there are questions concerning measurement results: In order to provide correlation data, the test shall be conducted under condition of 20±2°C of temperature, 60 to 70% relative humidity, and 86 to 106kPa of air pressure.

Stages	Precautions	Technical considerations
1.Circuit Design	Verification of operating environment, electrical rating and performance 1. A malfunction in medical equipment, spacecraft, nuclear reactors, etc. may cause serious harm to human life or have severe social ramifications. As such, any capacitors to be used in such equipment may require higher safety and/or reliability considerations and should be clearly differentiated from components used in general purpose applications. Operating Voltage (Verification of Rated voltage) 1. The operating voltage for capacitors must always be lower	
	than their rated values. If an AC voltage is loaded on a DC voltage, the sum of the two peak voltages should be lower than the rated value of the capacitor chosen. For a circuit where both an AC and a pulse voltage may be present, the sum of their peak voltages should also be lower than the capacitor's rated voltage. 2. Even if the applied voltage is lower than the rated value, the reliability of capacitors might be reduced if either a high frequency AC voltage or a pulse voltage having rapid rise time is present in the circuit.	
2.PCB Design	Pattern configurations (Design of Land-patterns) 1. When capacitors are mounted on a PCB, the amount of solder used (size of fillet) can directly affect capacitor performance. Therefore, the following items must be carefully considered in the design of solder land patterns: (1) The amount of solder applied can affect the ability of chips to withstand mechanical stresses which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads which in turn determines the amount of solder necessary to form the fillets. (2) When more than one part is jointly soldered onto the same land or pad, the pad must be designed so that each component's soldering point is separated by solder-resist.	1.The following diagrams and tables show some examples of recommended patterns to prevent excessive solder amourts.(larger fillets which extend above the component end terminations) Examples of improper pattern designs are also shown. (1) Recommended land dimensions for a typical chip capacitor land patterns for PCBs Land pattern Chip capacitor Solder-resist Chip capacitor Chip capacitor Chip capacitor Solder-resist Chip capacitor Type 107 212 316 325 L 1.6 2.0 3.2 3.2 Size W 0.8 1.25 1.6 2.5 A 0.8~1.0 1.0~1.4 1.8~2.5 1.8~2.5 B 0.5~0.8 0.8~1.5 0.8~1.7 0.8~1.7 C 0.6~0.8 0.9~1.2 1.2~1.6 1.8~2.5 Recommended land dimensions for reflow-soldering (unit: mm)
		Type 063 105 107 212 316 325 432 L 0.6 1.0 1.6 2.0 3.2 3.2 4.5 W 0.3 0.5 0.8 1.25 1.6 2.5 3.2 A 0.20~0.30 0.45~0.55 0.6~0.8 0.8~1.2 1.8~2.5 1.8~2.5 2.5~3.5 B 0.20~0.30 0.40~0.50 0.6~0.8 0.8~1.2 1.0~1.5 1.0~1.5 1.5~1.8 C 0.25~0.40 0.45~0.55 0.6~0.8 0.9~1.6 1.2~2.0 1.8~3.2 2.3~3.5 Excess solder can affect the ability of chips to withstand mechanical stresses. Therefore, please take proper precautions when designing land-patterns.

ıу	pe	316 (4 Circuits)	212 (4 Circuits)	\	
Size	L	3.2	2.0		
ŝ	W	1.6	1.25		
	а	0.7~0.9	0.5~0.6		
	b	1	0.5~0.6		
	С	0.4~0.5	0.2~0.3		
	d	0.8	0.5		
				' a	
Ту	/ре	212 (2 circuits)	110 (2 circuits)		
Size	L	2.0	1.37		7-7-
ŝ	W	1.25	1.0	a	
	а	0.5~0.6	0.35~0.45		→
	b	0.5~0.6	0.55~0.65		a
	С	0.5~0.6	0.3~0.4		p d
	d	1.0	0.64		a Î

Stages	Precautions		Technical consi	derations	
2.PCB Design		(2) Examples	of good and bad solder applica	ition	
		Items	Not recommended	Recommended	
		Mixed mounting of SMD and leaded components	Lead wire of component	Solder-resist	
		Component placement close to the chassis	Chassis Solder(for grounding)	Solder-resist	
		Hand-soldering of leaded components near mounted components	Lead wire of component- Soldering iron	Solder-resist	
		Horizontal component placement		Solder-resist	
	Pattern configurations (Capacitor layout on panelized [breakaway] PC boards) 1. After capacitors have been mounted on the boards, chips can	1-1. The following are examples of good and bad capacitor layout; SMD capacitors should be located to minimize any possible mechanical stresses from board warp or deflection.			
	be subjected to mechanical stresses in subsequent manufac-		Not recommended	Recommended	
	turing processes (PCB cutting, board inspection, mounting of additional parts, assembly into the chassis, wave soldering the reflow soldered boards etc.) For this reason, planning pattern configurations and the position of SMD capacitors should be carefully performed to minimize stress.	Deflection of the board		Position the component at a right angle to the direction of the mechanical stresses that are anticipated.	
	should be carefully performed to minimize stress.	1-2. To layout the capacitors for the breakaway PC board, it should be noted that the amount of mechanical stresses given will vary depending on capacitor layout. The example below shows recommendations for better design.			
		Perforati	on C C A Slit	D B	
			Magnitude of stress	A>B = C>D>E	
		the capacitors	can vary according to the me	tions, the amount of mechanical stress on ethod used. The following methods are tressful: push-back, slit, V-grooving, and ayout must also consider the PCB splitting	

	Multilayer Ceramic Capacitors				
Stages	Precautions		Technical consider	ations	
3.Considerations for automatic placement	Adjustment of mounting machine 1. Excessive impact load should not be imposed on the capacitors when mounting onto the PC boards. 2. The maintenance and inspection of the mounters should be conducted periodically.	capacitors, cau before lowering (1)The lower limit board after corr (2)The pick-up pre (3)To reduce the a supporting pins	sing damage. To avoid this, the fithe pick-up nozzle: of the pick-up nozzle should be a certing for deflection of the board. essure should be adjusted betwee amount of deflection of the board of	n 1 and 3 N static loads. aused by impact of the pick-up nozzle, nder the PC board. The following dia-	
			Not recommended	Recommended	
		Single-sided mounting	Cracks	Supporting pin-U	
		Double-sided mounting	Solder peeling Cracks	Supporting plin	
		As the alignment pin wears out, adjustment of the nozzle height can cause chipping or cracking of the capacitors because of mechanical impact on the capacitors. To avoid this, the monitoring of the width between the alignment pin in the stopped position, and maintenance, inspection and replacement of the pin should be conducted periodically.			
	Selection of Adhesives 1. Mounting capacitors with adhesives in preliminary assembly, before the soldering stage, may lead to degraded capacitor characteristics unless the following factors are appropriately checked; the size of land patterns, type of adhesive, amount applied, hardening temperature and hardening period. Therefore, it is imperative to consult the manufacturer of the adhe-	shrinkage perce on the capacitor to the board ma should be noted	entage of the adhesive and that of rs and lead to cracking. Moreover,	the capacitors may result in stresses too little or too much adhesive applied acement, so the following precautions	
	sives on proper usage and amounts of adhesive to use.	a. The adhesive s solder process. b. The adhesive s c. The adhesive s d. The adhesive s e. The adhesive s	hould be strong enough to hold par	kness consistency.	
		g. The adhesive should have excellent insulation characteristics. h. The adhesive should not be toxic and have no emission of toxic gasses.			
		(2)The recommen	nded amount of adhesives is as fol	lows;	
		Figure	212/316 case size	s as examples	
		a .	0.3mm		
		b c	100 ~120 Adhesives should no	·	
		Amou	nt of adhesive A	fter capacitors are bonded	

Stages	Precautions	Technical considerations
Soldering	Selection of Flux 1. Since flux may have a significant effect on the performance of capacitors, it is necessary to verify the following conditions prior to use; (1)Flux used should be with less than or equal to 0.1 wt% (equivelent to chroline) of halogenated content. Flux having a strong acidity content should not be applied. (2)When soldering capacitors on the board, the amount of flux applied should be controlled at the optimum level. (3)When using water-soluble flux, special care should be taken to properly clean the boards.	 1-1. When too much halogenated substance (Chlorine, etc.) content is used to activate the flux, or highly acidic flux is used, an excessive amount of residue after soldering may lead to corrosion of the terminal electrodes or degradation of insulation resistance on the surface of the capacitors. 1-2. Flux is used to increase solderability in flow soldering, but if too much is applied, a large amount of flux gas may be emitted and may detrimentally affect solderability. To minimize the amount of flux applied, it is recommended to use a flux-bubbling system. 1-3. Since the residue of water-soluble flux is easily dissolved by water content in the air, the residue on the surface of capacitors in high humidity conditions may cause a degradation of insulation resistance and therefore affect the reliability of the components. The cleaning methods and the capability of the machines used should also be considered carefully when selecting water-soluble flux.
	Soldering Temperature, time, amount of solder, etc. are specified in accordance with the following recommended conditions.	1-1. Preheating when soldering Heating: Ceramic chip components should be preheated to within 100 to 130°C of the soldering. Cooling: The temperature difference between the components and cleaning process should not be greater than 100°C. Ceramic chip capacitors are susceptible to thermal shock when exposed to rapid or concentrated heating or rapid cooling. Therefore, the soldering process must be conducted with great care so as to prevent malfunction of the components due to excessive thermal shock.
	And please contact us about peak temperature when you use lead-free paste.	Recommended conditions for soldering [Reflow soldering] Temperature profile Temperature('C) Temperature (C) 200 Peak 260'C max Peak 260'C max 10 sec max Over 1 minute Over 1 minute Within 10 seconds Temperature('C) 10 sec max Peak 260'C max Freheating Over 1 minute Over 1 minute Within 10 seconds Caution
		1. The ideal condition is to have solder mass (fillet) controlled to 1/2 to 1/3 of the thick ness of the capacitor, as shown below: Capacitor PC board 2. Because excessive dwell times can detrimentally affect solderability, soldering duration should be kept as close to recommended times as possible. [Wave soldering]
		Temperature profile Temperature (C) 300 Peak 260°C max
		Caution 1. Make sure the capacitors are preheated sufficiently. 2. The temperature difference between the capacitor and melted solder should not be greater than 100 to 130°C 3. Cooling after soldering should be as gradual as possible. 4. Wave soldering must not be applied to the capacitors designated as for reflow soldering only.

Stages	Precautions	Technical considerations
4. Soldering		[Hand soldering] Temperature profile Temperature (C) 300 Preheating Over 1 minute Within 3 seconds Temperature(C) 400 400 4T = 350C max 3 sec max 3 sec max Gradually cooling (% 4T = 190C (32:16Type max), 4T = 130C (32:27ype min)) % It is recommended to use 20W soldering iron and the tip is 14 or less. The soldering iron should not directly touch the components. Note: The above profiles are the maximum allowable soldering condition, therefore these profiles a not always recommended. Caution 1. Use a 20W soldering iron with a maximum tip diameter of 1.0 mm. 2. The soldering iron should not directly touch the capacitor.
5.Cleaning	Cleaning conditions 1. When cleaning the PC board after the capacitors are all mounted, select the appropriate cleaning solution according to the type of flux used and purpose of the cleaning (e.g. to remove soldering flux or other materials from the production process.) 2. Cleaning conditions should be determined after verifying, through a test run, that the cleaning process does not affect the capacitor's characteristics.	1. The use of inappropriate solutions can cause foreign substances such as flux residue to adhere to the capacitor or deteriorate the capacitor's outer coating, resulting in a degradation of the capacitor's electrical properties (especially insulation resistance). 2. Inappropriate cleaning conditions (insufficient or excessive cleaning) may detrimentally affect the performance of the capacitors. (1)Excessive cleaning In the case of ultrasonic cleaning, too much power output can cause excessive vibration of the PC board which may lead to the cracking of the capacitor or the soldered portion, or decrease the terminal electrodes' strength. Thus the following conditions should be carefully checked; Ultrasonic output Below 20 W/& Ultrasonic frequency Below 40 kHz Ultrasonic washing period 5 min. or less
6.Post cleaning processes	1. With some type of resins a decomposition gas or chemical reaction vapor may remain inside the resin during the hardening period or while left under normal storage conditions resulting in the deterioration of the capacitor's performance. 2. When a resin's hardening temperature is higher than the capacitor's operating temperature, the stresses generated by the excess heat may lead to capacitor damage or destruction. The use of such resins, molding materials etc. is not recommended.	
7.Handling	Breakaway PC boards (splitting along perforations) 1. When splitting the PC board after mounting capacitors and other components, care is required so as not to give any stresses of deflection or twisting to the board. 2. Board separation should not be done manually, but by using the appropriate devices. Mechanical considerations 1. Be careful not to subject the capacitors to excessive mechanical shocks. (1)If ceramic capacitors are dropped onto the floor or a hard surface, they should not be used. (2)When handling the mounted boards, be careful that the mounted components do not come in contact with or bump against other boards or components.	

Stages	Precautions	Technical considerations
8.Storage conditions	Storage 1. To maintain the solderability of terminal electrodes and to keep the packaging material in good condition, care must be taken to control temperature and humidity in the storage area. Humidity should especially be kept as low as possible. Recommended conditions Ambient temperature Below 40°C Humidity Below 70% RH The ambient temperature must be kept below 30°C. Even under ideal storage conditions capacitor electrode solderability decreases as time passes, so should be used within 6 months from the time of delivery. Ceramic chip capacitors should be kept where no chlorine or sulfur exists in the air. 2. The capacitance value of high dielectric constant capacitors (type 2 &3) will gradually decrease with the passage of time, so this should be taken into consideration in the circuit design. If such a capacitance reduction occurs, a heat treatment of 150°C for 1hour will return the capacitance to its initial level.	If the parts are stored in a high temperature and humidity environment, problems such as reduced solderability caused by oxidation of terminal electrodes and deterioration of taping/packaging materials may take place. For this reason, components should be used within 6 months from the time of delivery. If exceeding the above period, please check solderability before using the capacitors.